

SPECIFICATIONS

1. Application

- 1) This document is applicable to the crystal unit that are delivered to GOERTEK ELECTRONIC CO LTD from Seiko Epson Corp.
- 2) This product complies with RoHS Directive.
- 3) This Product supplied (and any technical information furnished, if any) by Seiko Epson Corporation shall not be used for the development and manufacture of weapon of mass destruction or for other military purposes. Making available such products and technology to any third party who may use such products or technologies for the said purposes are also prohibited.
- 4) This product listed here is designed as components or parts for electronics equipment in general consumer use. We do not expect that any of these products would be incorporated or otherwise used as a component or part for the equipment, which requires an systems, and medical equipment, the functional purpose of which is to keep extra high reliability, such as satellite, rocket and other space life.

2. Product No. / Model

The product No. of this crystal unit is Q24FA20H0028900.
The model is FA-20H.

3. Packing

It is subject to the packing standard of Seiko Epson Corp.

4. Warranty

Defective parts which originate with us are replaced free of charge in the case of defects being found with 12 months after delivery.

5. Amendment and/or termination

Amendment and/or termination of this specification is subject to the agreement between the two parties.

6. Contents

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[1] Absolute maximum ratings

No.	Item	Symbol	Rating value			Unit	Note
			Min.	Typ.	Max.		
1	Storage temperature range	T_stg	- 40		+ 125	°C	Depends on the Environmental characteristics specifications.

[2] Operating range

No.	Item	Symbol	Rating value			Unit	Note
			Min.	Typ.	Max.		
1	Operating temperature range	T_use	- 40		+ 85	°C	
2	Level of drive	DL		100	200	μW	Recommended : 100 μW

[3] Static characteristics

No.	Item	Symbol	Value	Unit	Conditions
1	Nominal Frequency	f_nom	26	MHz	Fundamental
2	Frequency tolerance	f_tol	± 10	× 10 ⁻⁶	CL = 9pF Ta = + 25 ± 3°C DL = 100 μW Not include aging
3	Motional resistance	R1	60 Max.(25 < f_nom ≤ 30 MHz)	Ω	π circuit IEC 60444-2 Ta = Operating temperature range DL = 100 μW
4	Shunt capacitance	C0	2.0 Max.	pF	π circuit and N.A.
5	Frequency temperature characteristics	f_tem	± 18	× 10 ⁻⁶	Ta = Operating temperature range (Ref. at Ta = + 25 °C ± 3 °C) DL = 100 μW
6	Isolation resistance	IR	500 Min.	MΩ	DC 100 V± 15, 60 seconds Between terminal # 1 and terminal # 3
7	Frequency Aging	f_age	± 1 (12 < f_nom ≤ 40 MHz) ± 3 (40 < f_nom ≤ 48 MHz)	× 10 ⁻⁶ /year	Ta = + 25 °C ± 3 °C

[4] Environmental and mechanical characteristics

(The company evaluation condition : We evaluate it by the following examination item and examination condition.)

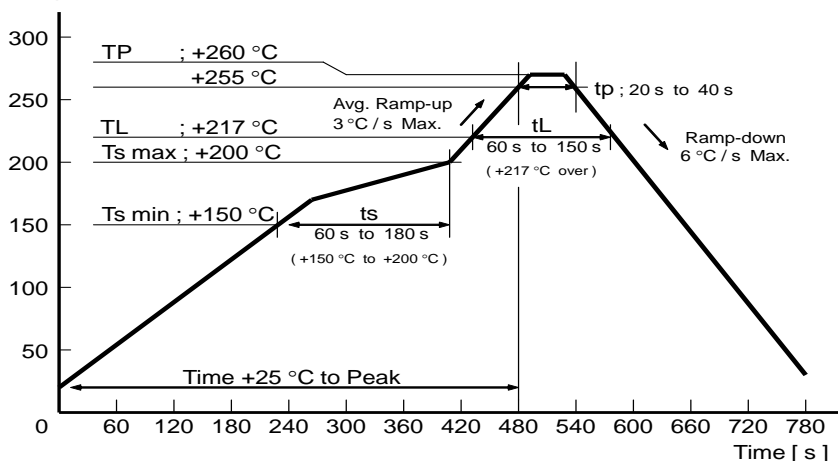
No.	Item	Value * 1 * 2	Test Conditions
		$\Delta f / f [1 \times 10^{-6}]$	
1	Shock	* 3 ± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	150 g dummy Jig (ETC Standard) drop from 1 500 mm height on the Concrete 3 directions 10 times
2	Vibration	* 3 ± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	10 Hz to 55 Hz amplitude 0.75 mm 55 Hz to 500 Hz acceleration 98 m/s ² 10 Hz → 500 Hz → 10 Hz 15 min./cycle 6 h (2 hours , 3 directions)
3	High temperature storage	* 3 ± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	+ 85 °C × 1 000 h
4	Low temperature storage	* 3 ± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	- 40 °C × 1 000 h
5	Temperature cycle	* 3 ± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	- 40 °C ↔ + 85 °C 30 minutes at each temp. 100 cycle
6	Temperature humidity storage	* 3 ± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	+ 85 °C × 85 %RH × 1 000 h
7	Resistance to soldering heat	± 2 ($12 < f_{nom} \leq 40$ MHz) ± 5 ($40 < f_{nom} \leq 48$ MHz)	For convention reflow soldering furnace (3 times)
8	Substrate bending	No peeling-off at a soldered part	Bend width reaches 3 mm and hold for 5 s ± 1 s × 1 time Ref. IEC 60068-2-21
9	Shear	No peeling-off at a soldered part	10 N press for 10 s ± 1 s Ref. IEC 60068-2-21
10	Pull – off	No peeling-off at a soldered part	10 N press for 10 s ± 1 s Ref. IEC 60068-2-21
11	Solderability	Terminals must be 95 % covered with fresh solder.	Dip termination into solder bath at + 235 °C ± 5 °C for 5 s (Using Rosin Flux)

< Notes >

- * 1 Each test done independently.
- * 2 Measuring 2 h to 24 h later leaving in room temperature after each test.
- * 3 Item No.1 to No.6 shall be tested after following pre conditioning.
Measuring 24 h later leaving in room temperature after Pre conditioning.
Pre conditioning : Reflow 3 times.
- Item No.1 to No.7, Shift motional resistance at after above tests should be less than 20 % or less than 10 Ω.

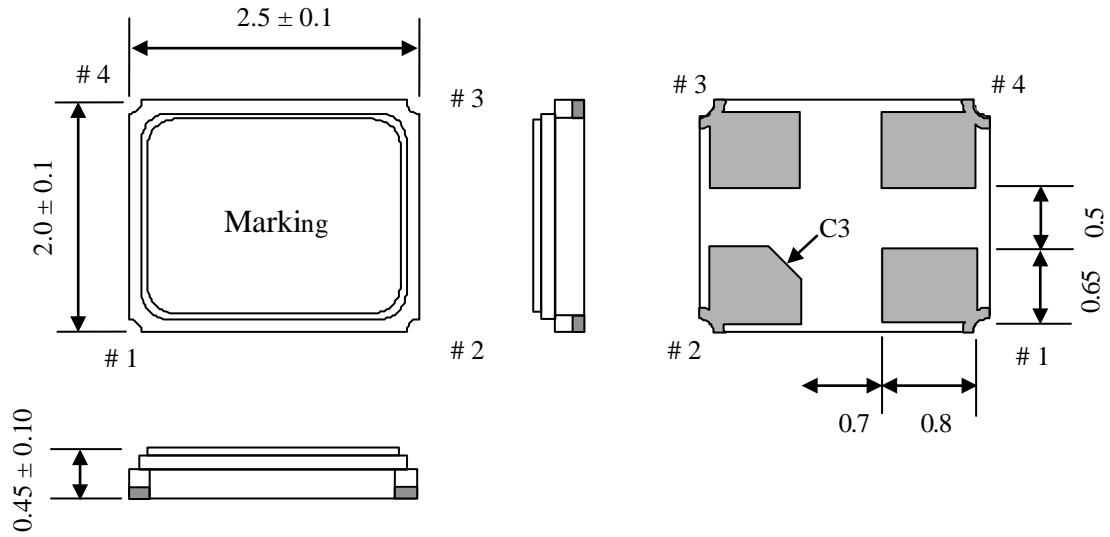
◆ Reflow condition (follow to IPC/JEDEC J-STD-020C)

Temperature [°C]



[5] Dimensions and Circuit

1) Dimension

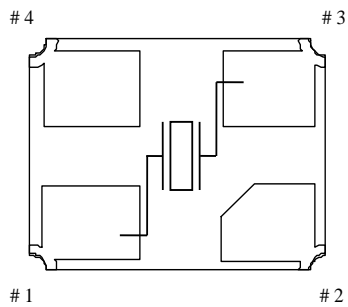


Pin connection

# 1,# 3	IN/OUT
# 2,# 4	GND

2) Circuit

(Top View)



Terminal

1, # 3 : X'tal

2, # 4 : GND(are connected to the cover)

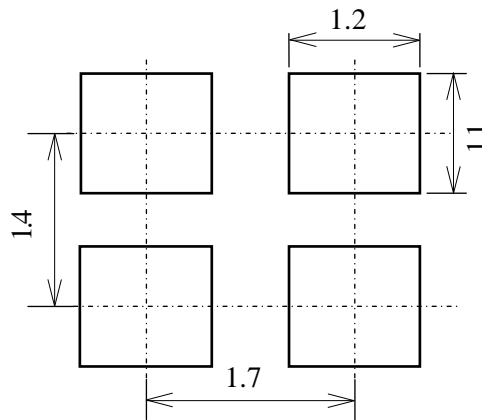
Type : FA-20H

Terminal treatment : Au plate

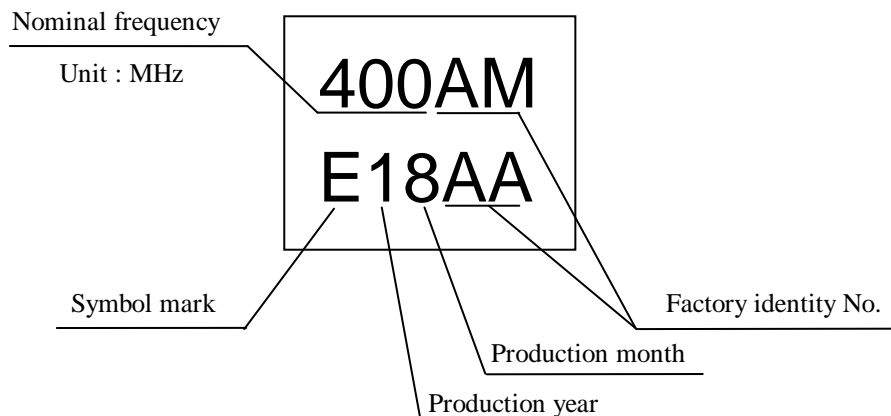
Unit : 1 = 1mm

[6] Recommended soldering pattern and Marking layout

1) Recommended soldering pattern



2) Marking layout



Production month

January	February	October	November	December
1	2	X	Y	Z

- Nominal frequency is only one example.
- Nominal frequency omits the figure below the first place of decimals.
ex) 40 MHz [400]
- The above marking layout shows only marking contents and their approximate position and it is not for font, size and exact position.

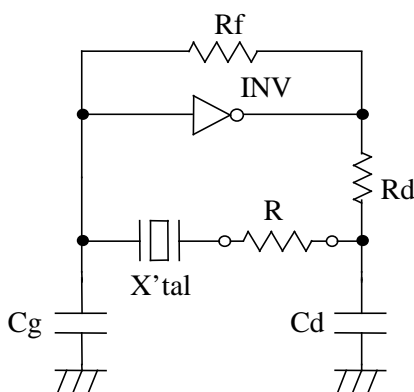
Type : FA-20H

Unit : 1 = 1 mm

[7] Notes

1. Max three (3) times re-flow is allowed. Its recommended to manually solder when not enough/no solder detected.(Using soldering iron at +350 °C Max × within 5 seconds)
2. Patterning on a board should follow our company recommended pattern.
3. Too much exciting shock or vibration may cause deterioration on damage.
The product may damage depends on the condition such as a shock in assembly machinery.
Please check your process condition in advance to minimize and maintain the shock level.
4. It is recommended to do patterning to the oscillator as short as possible. Abnormal oscillation may happened if the line is too long.
5. Condensation may occur when products are used/stored under remarkable temperature change.
6. This product may be affected to ultrasonic cleaning. It is depends on the cleaning conditions (Cleaning machine type/power/time/content/position etc.). The warranty will not cover any damage due to this type of usage. Check conditions prior to use.
7. When the substrate of oscillation become dewy, the crystal frequency is changed or stopped. Please use under without the dewfall.
8. Applying excessive excitation Drive Level to the crystal Unit may cause deterioration damage.
9. Few data or readings taken at user side may be different from our company's data. Confirmation of the different value is necessary before application.
10. To avoid malfunction, no pattern across or near the crystal is allowed.
11. Start up time of oscillation may be increased or no oscillation may occur unless adequate negative resistance is allocated in the oscillation circuit In order to avoid this, please provide enough negative resistance to the circuit design.

How to check the negative resistance



- (1) Connect the resistor(R) to the circuit in series with the crystal Unit.
- (2) Adjust R so that oscillation can start (or stop).
- (3) Measure R when oscillation just start (or stop) in above (2).
- (4) Get the negative resistance
 $-R=R+CI$ value.
- (5) Recommended -R
 $[-R] > CI \times 5$

12. Please refer to packing specification for the storage method and packing standard.